

Heterogeneous integration of III-V and silicon devices for digital VLSI

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UCSB Solid State Technology Review

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Agenda

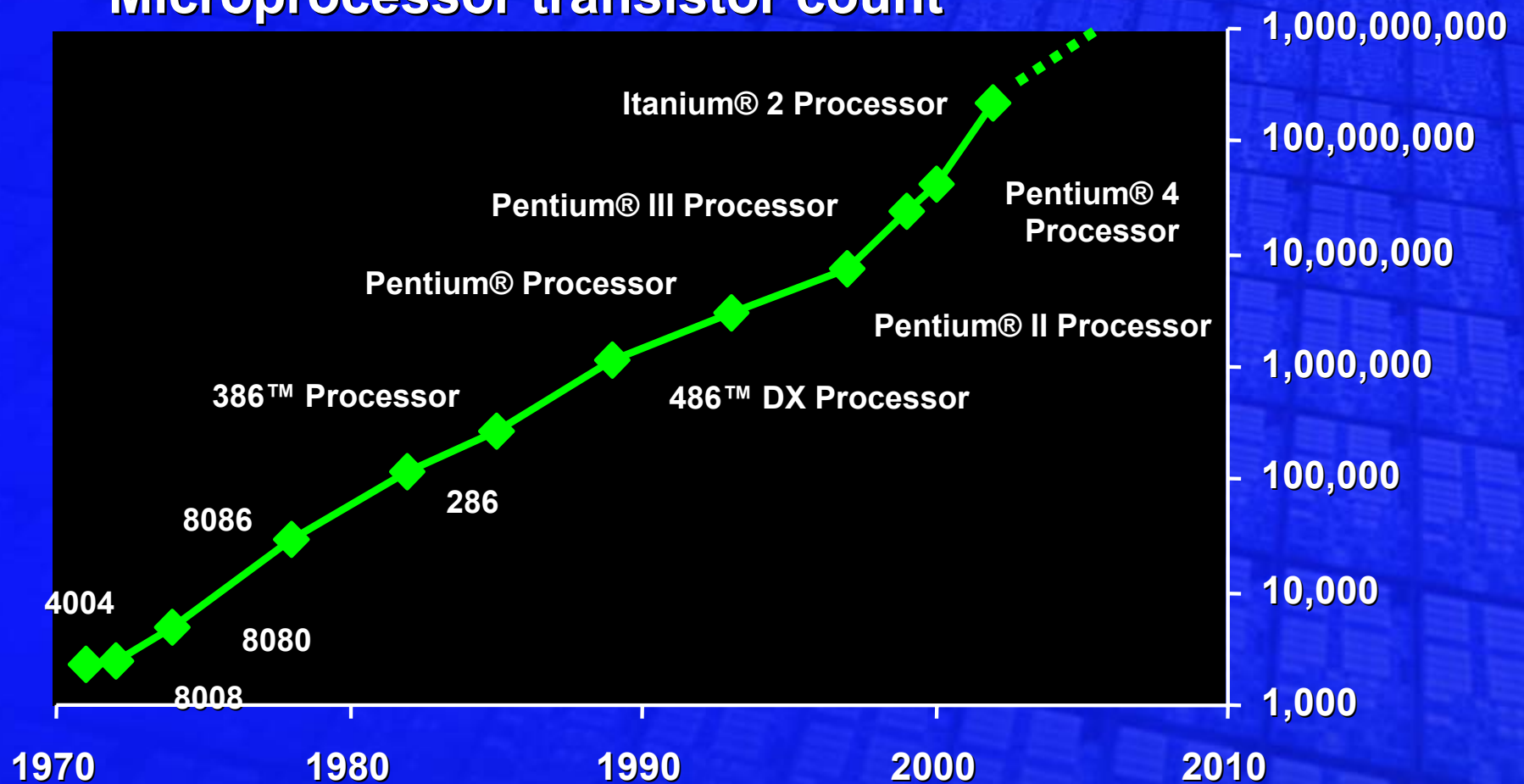
- **Microprocessor core and I/O speeds**
- **Electrical I/O**
- **Intel's optoelectronics research at universities**
- **III-V and optical interconnects**
- **Conclusions**
- **Acknowledgements**

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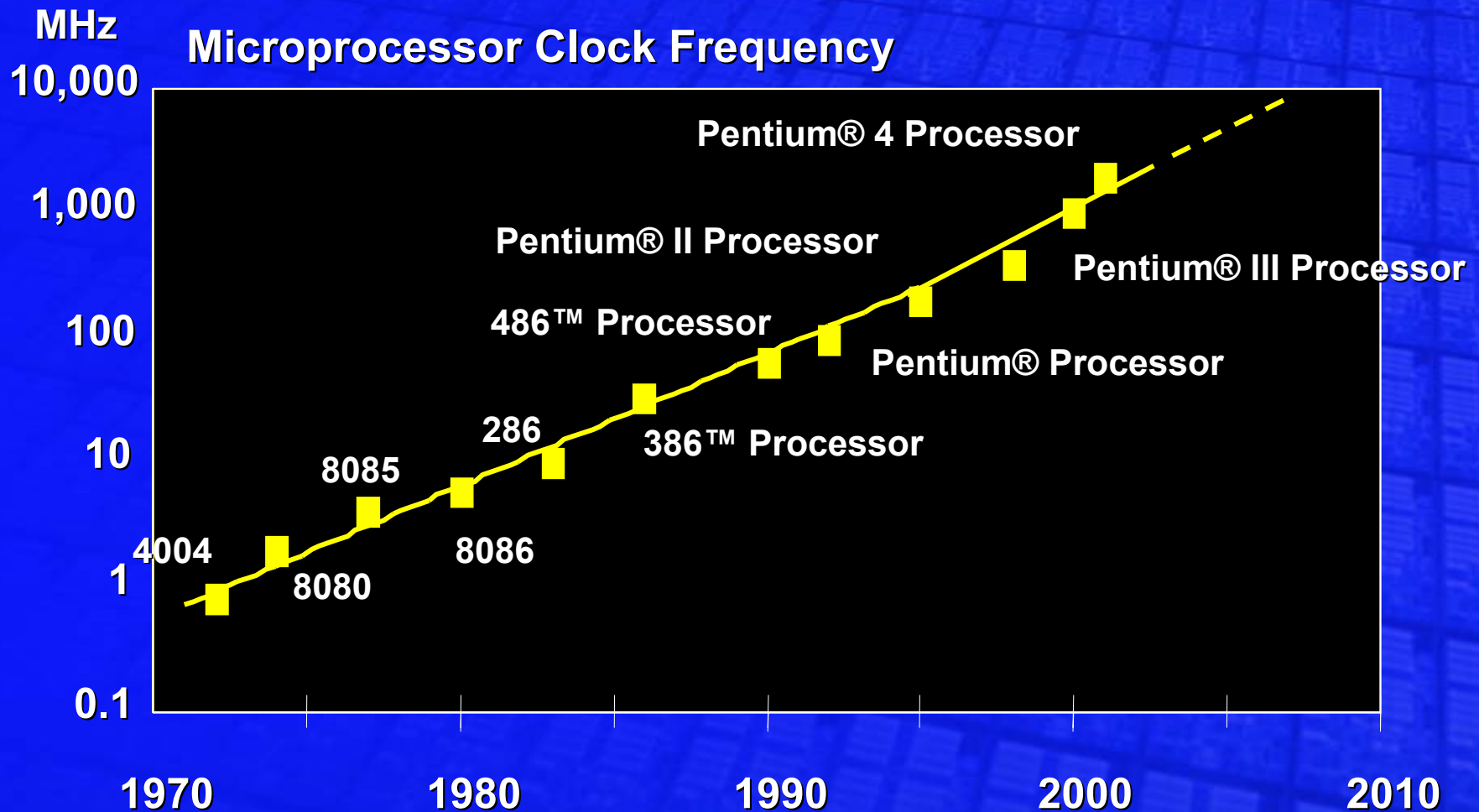
More Transistors per Chip

Microprocessor transistor count



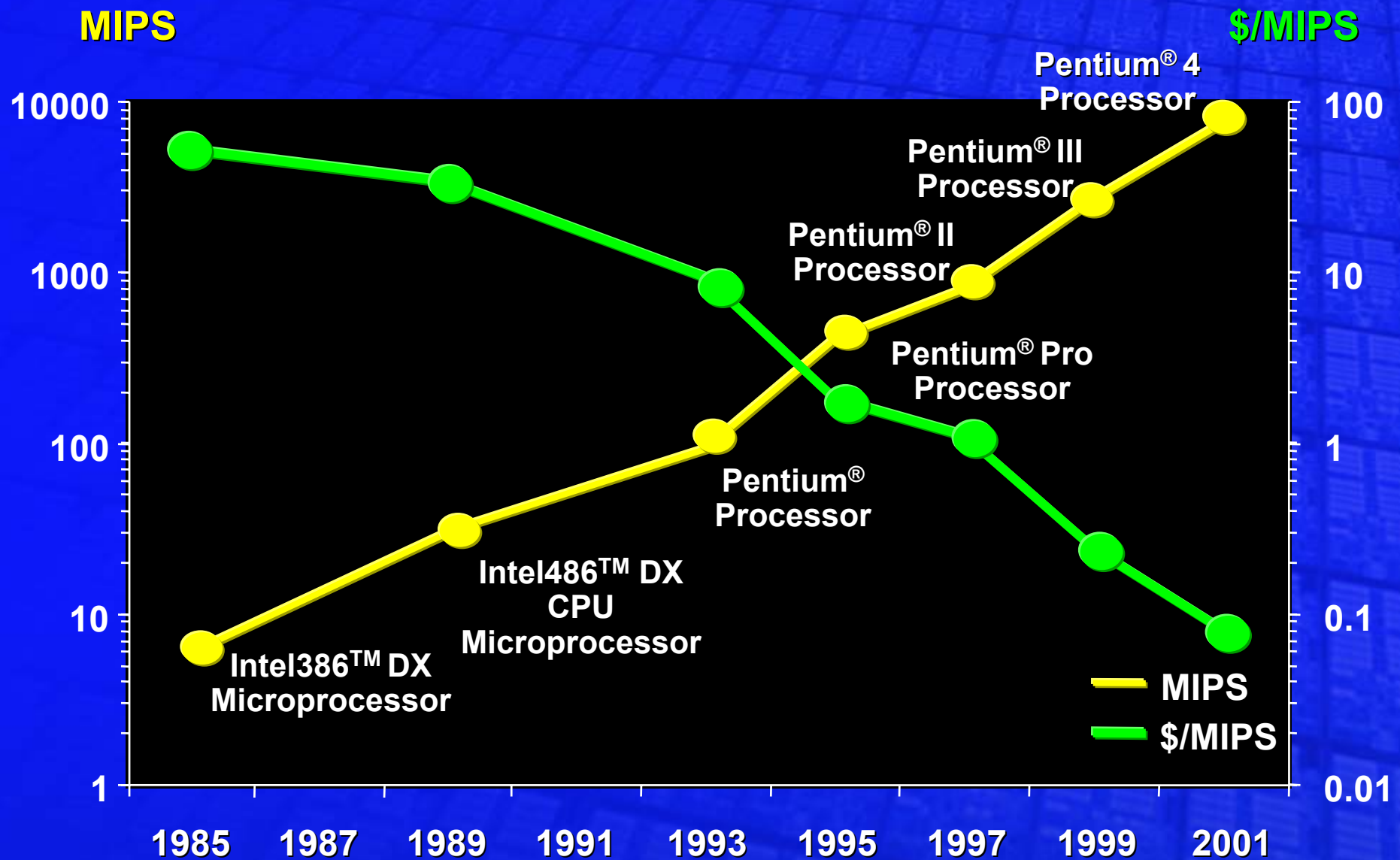
~ 1B transistor microprocessor by 2007

Faster Devices

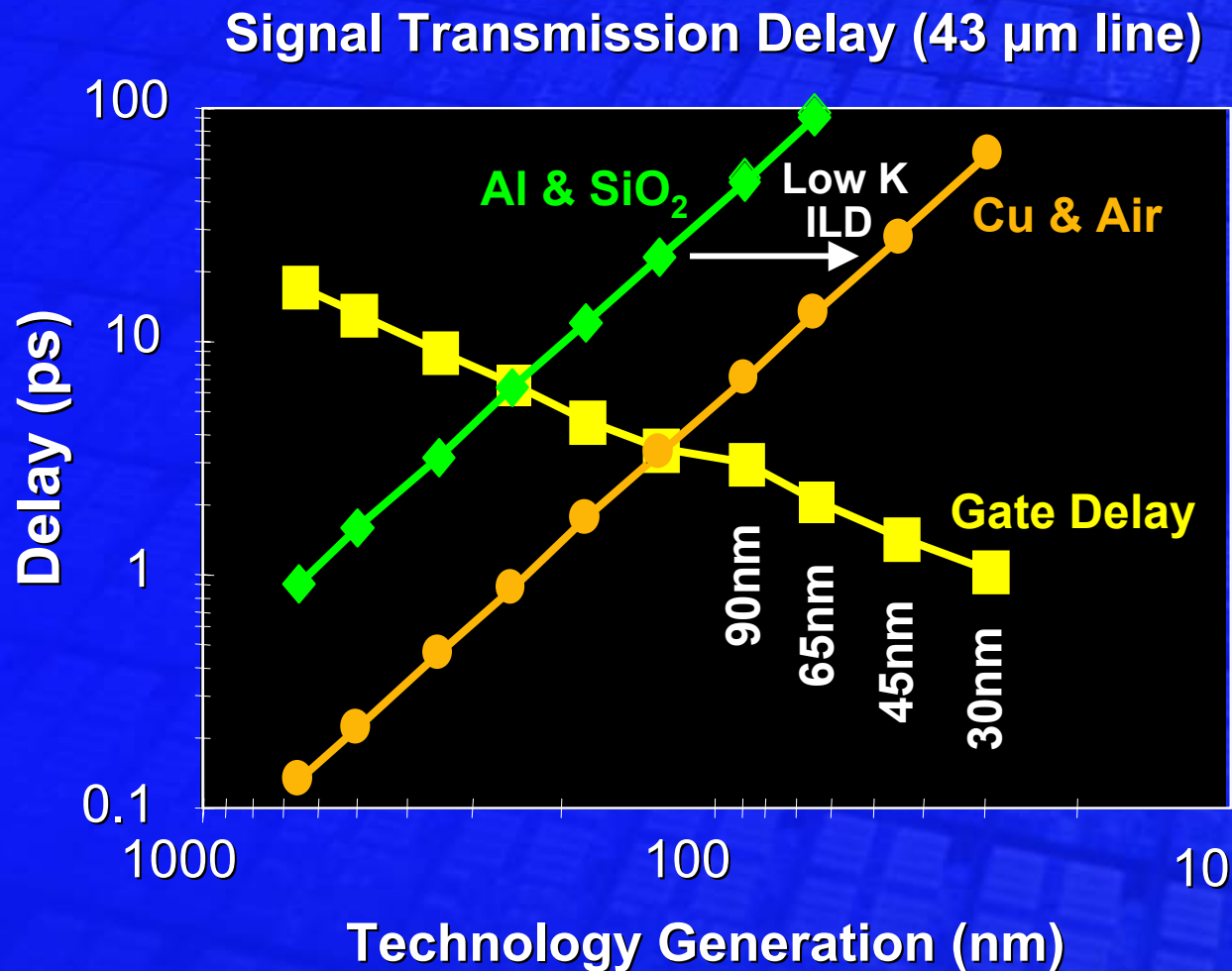


**Microprocessor clock frequency
trending to ~ 10GHz by 2007**

Higher Performance, Lower Cost

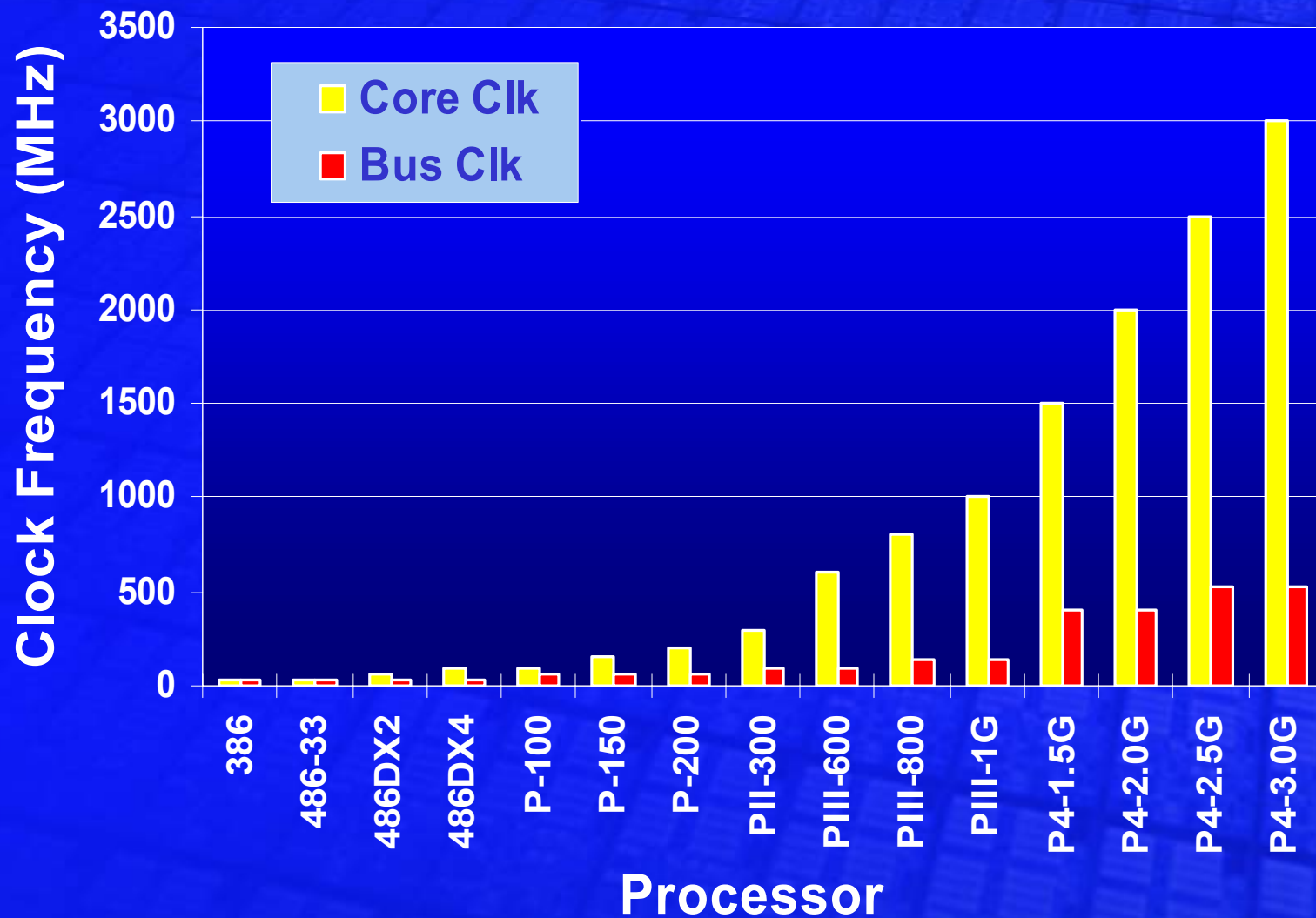


Interconnect Delay Challenge



Need process, circuit design and architectural innovations

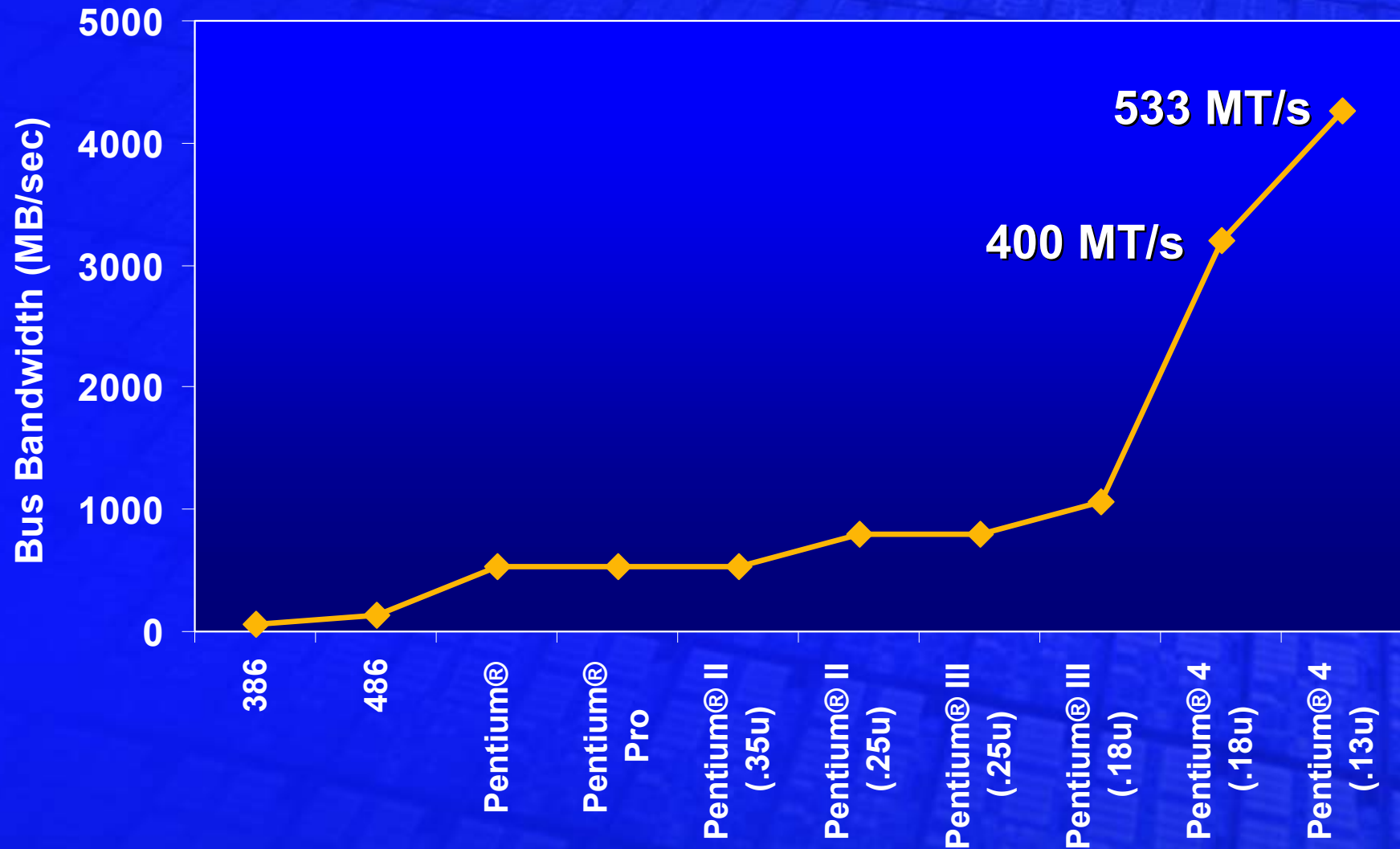
Processor Core Vs. Bus Clock



Bus frequency is not keeping up with the processor core

Bus Bandwidth Trend

K Bytes

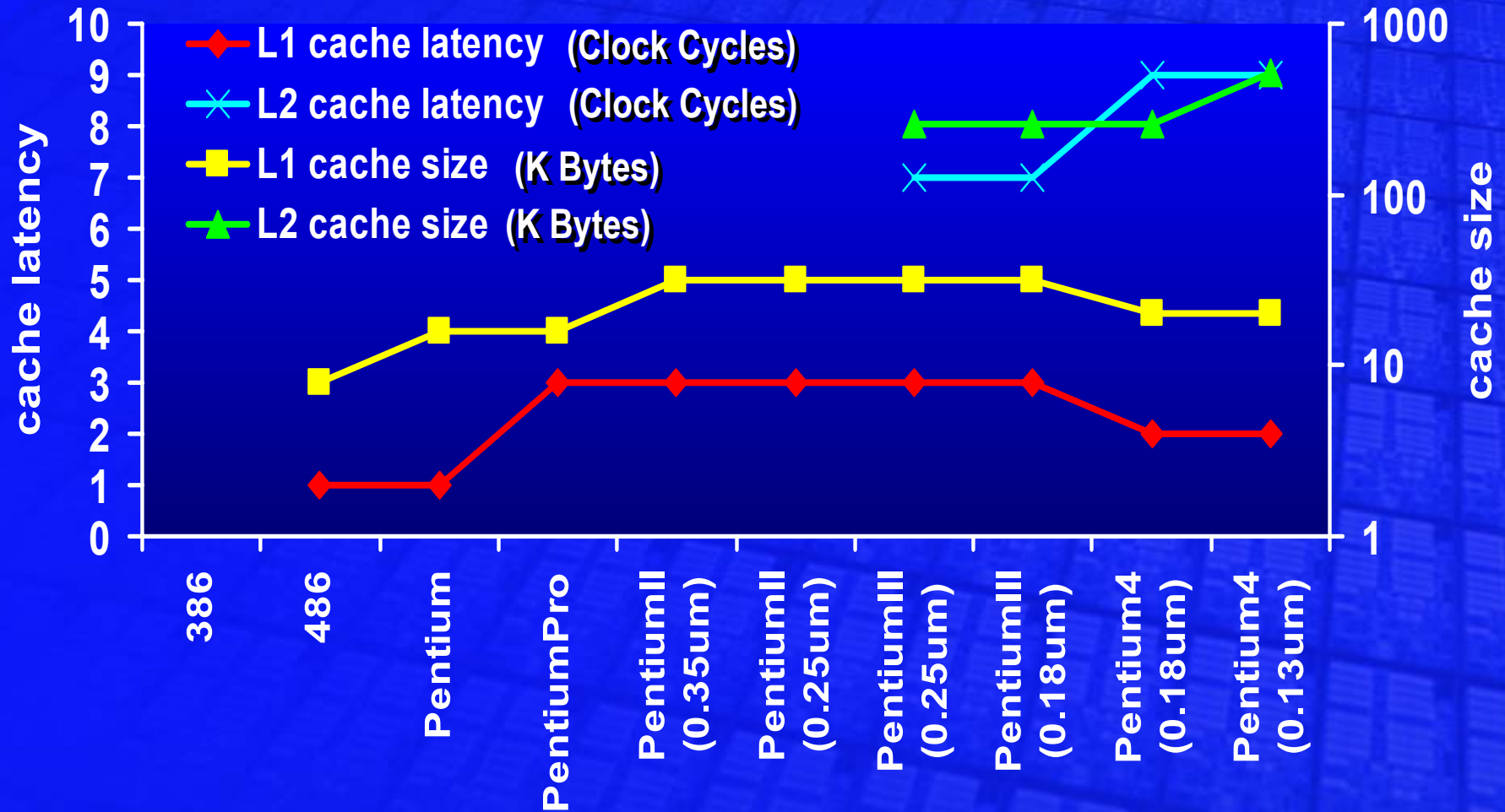


Memory And I/O Bandwidth Are Essential For High Performance

Combating the I/O bottleneck

- Large on chip caches reduce the requirement to go off chip
- Every generation of CMOS scaling increases on chip integration:
 - Reduces need to go off chip
- Advanced circuits to increase the reach of copper
- Advanced packaging keeps high speed components close to each other:
 - Reduces off chip interconnect length
- Optical interconnects for the ultimate in bandwidth, crosstalk and EMI

Cache Memory Trend



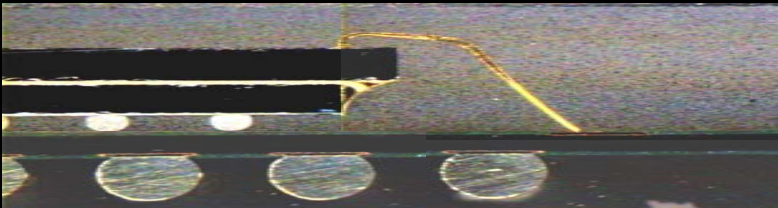
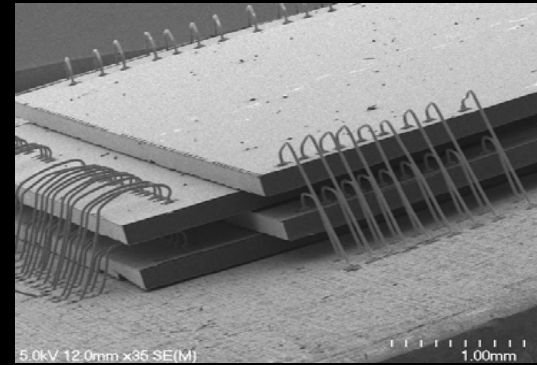
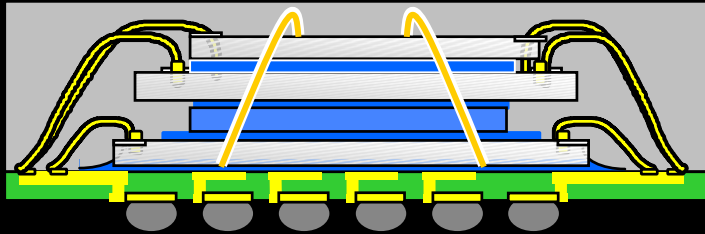
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memory gap

- Reduce average miss rates
- Reduce average memory access latency

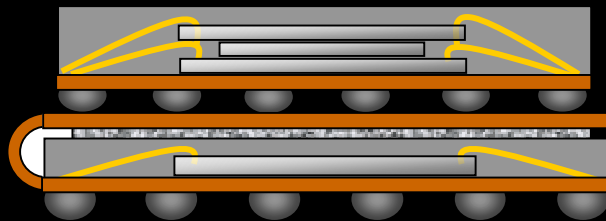
Integration via Packaging

Wirebond Stacked CSP



Flip Chip/Wirebond Stacked CSP

Folded Stacked CSP



Advanced packaging keep high speed devices
close to each other

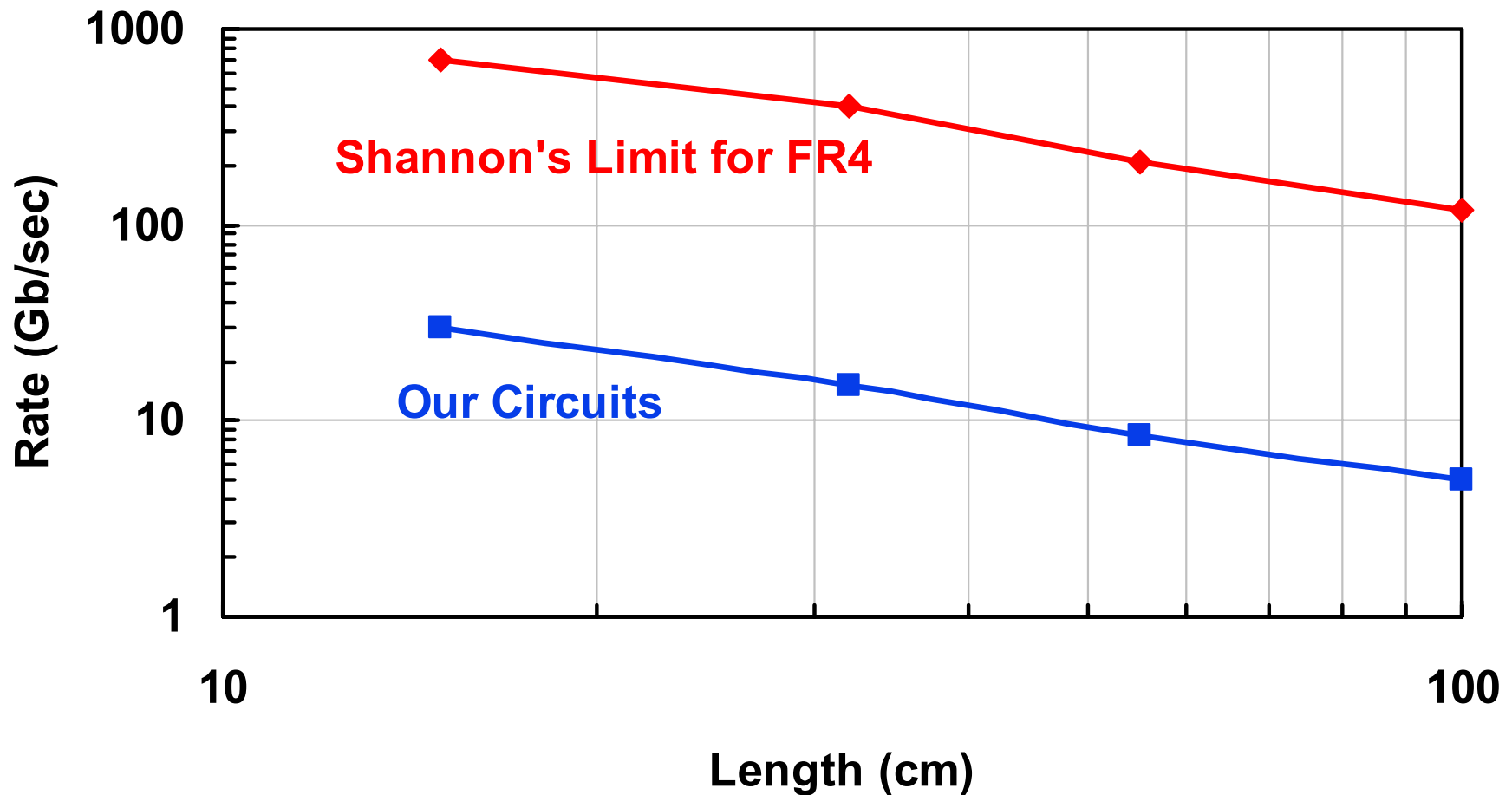
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Copper for signaling keeps going forward

- Chip-to-chip ~ .25m
- Intra-board ~.5m
- Inter-board ~ 1m
- Box-to-box ~10m
- Advanced circuit techniques
 - Pre-(distortion/emphasis)/Channel Equalization/High order modulation, etc.
 - PCB board material alternative to FR4.

Copper signaling



- Intel's copper signaling research

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Optoelectronics research

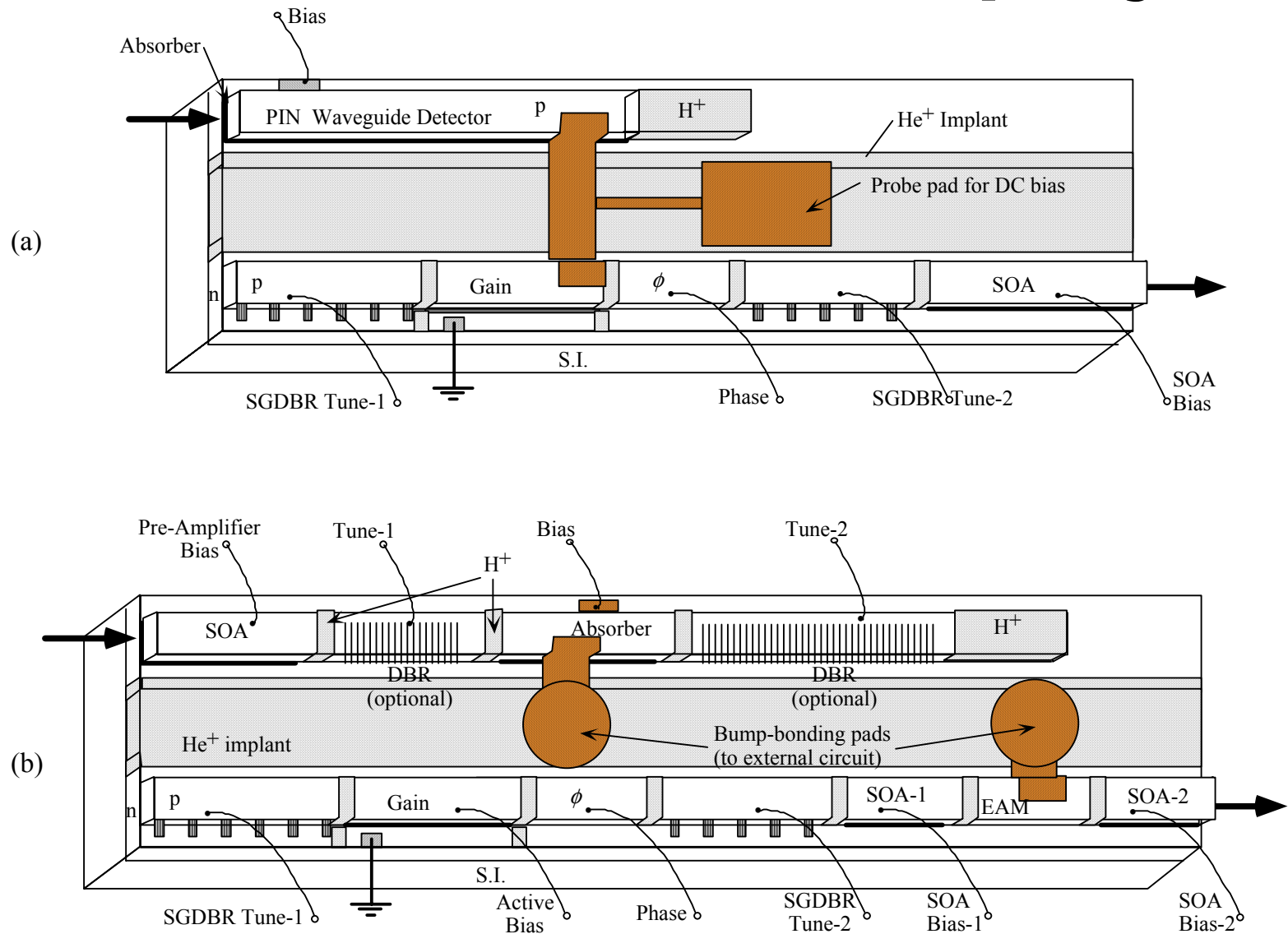
- Will highlight three research projects Intel is sponsoring:
 - UCSB – Prof Larry Coldren
 - Stanford - Prof David Miller
 - Caltech – Prof. Harry Atwater
- Research goals:
 - InP monolithic integration
 - Hybrid integration
 - Silicon nano-crystal research

Overview of UCSB project

John Hutchinson - RIR, George Bourianoff - ARP

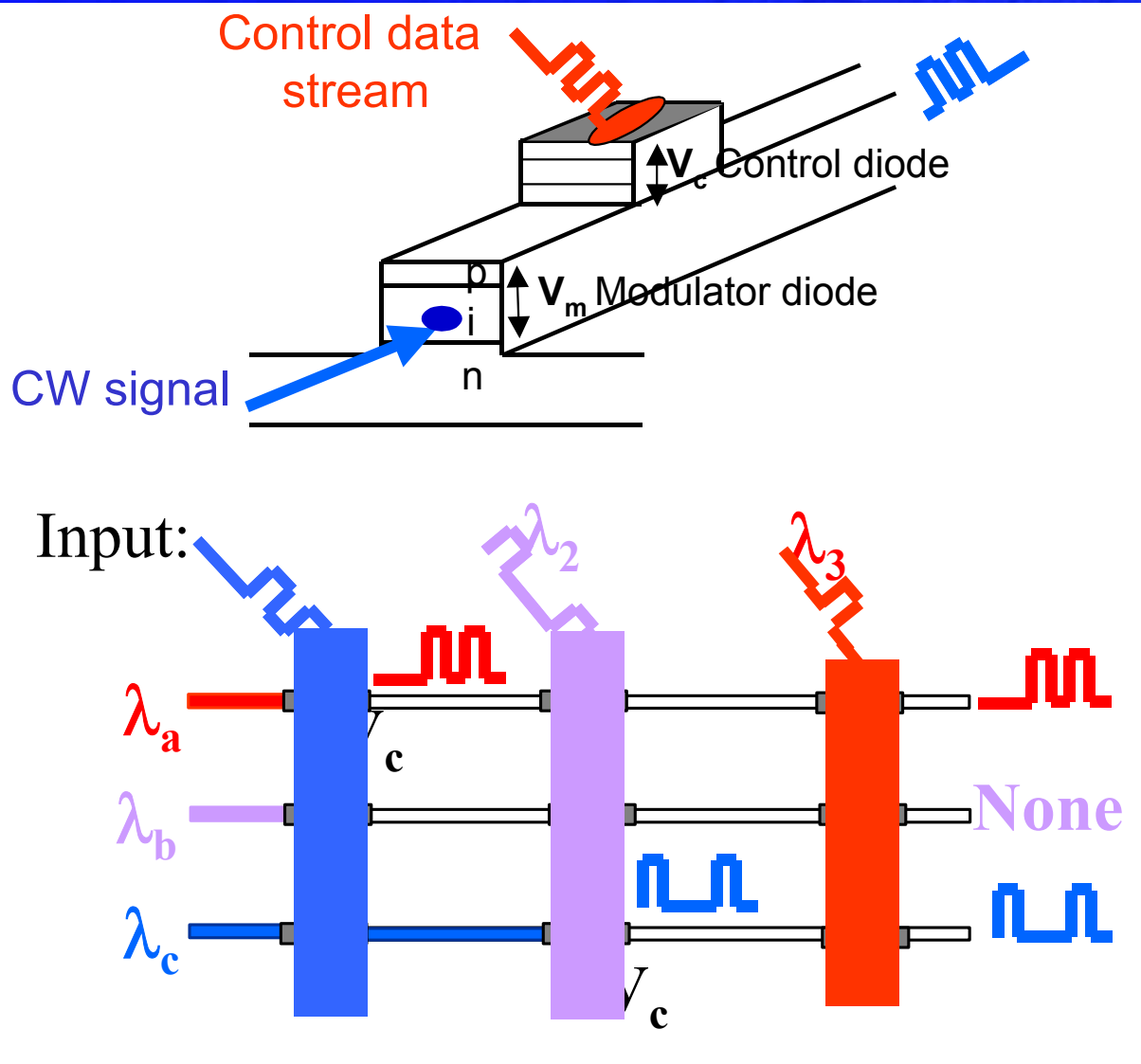
- **Widely tunable wavelength converter:**
Prof Larry Coldren
 - Ridge waveguide platform / PIN diode optical detector
 - a) Direct modulation b) Electro-Absorption Modulator
 - Widely-tunable SGDBR laser
 - Semiconductor Optical Amplifiers
 - Heterogeneous device and package integration
 - DC, rf testing

Intel – UCSB research project



•Widely tunable wavelength converter: Prof Larry Coldren

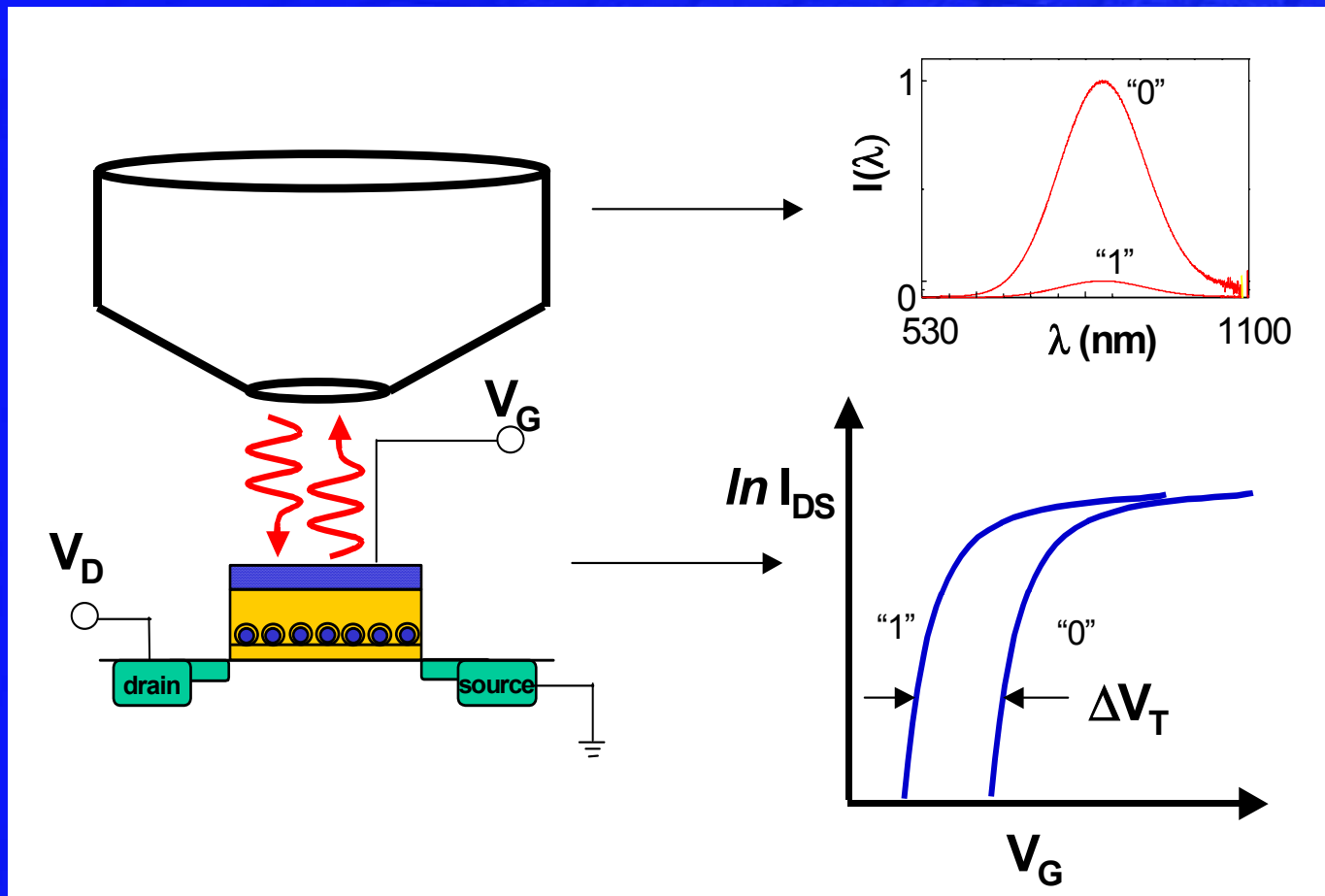
Intel – Stanford Project



- Evaluate the feasibility of opto-electronic wavelength converters based on integrated quantum well modulator/detector structures for use in 1.5 μm optical telecommunications at 40Gb/sec.

Concept for a wavelength converting crossbar switch. Here - two of the switches are enabled using the control voltage.

Overview of Caltech project



- Investigate design and fabrication of all optical memory cell
 - Silicon nano-crystal fabrication
 - Silicon processing at Intel
- Conduct advanced numerical simulation

Concept for an all optical memory cell

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Opportunities for III-V optoelectronics

PROS

- Virtually unlimited bandwidth:
- No signal crosstalk or EMI
- Latency is about comparable to electrical links

CONS

- High Cost
- Large Form Factor
- Expensive assembly and alignment

Adapting telecom grade optoelectronics to chip to chip Interconnects is an overkill and too costly

Optoelectronics

- Reinvent III-V optoelectronics technologies developed for telecommunications for mainstream high volume computers:
 - High volume reduces cost of niche components
 - Apply technologies like WDM to improve aggregate data rates:
 - Need low cost Heterogeneous integration techniques
- Need much less focus on loss, high power, dispersion etc as typical link lengths are < 20 inches

Silicon leads in electronic integration and high performance. III-V leads in optoelectronics. In high volume a marriage can only happen if the cost structures and form factors are synchronized

Optical and electronic signaling

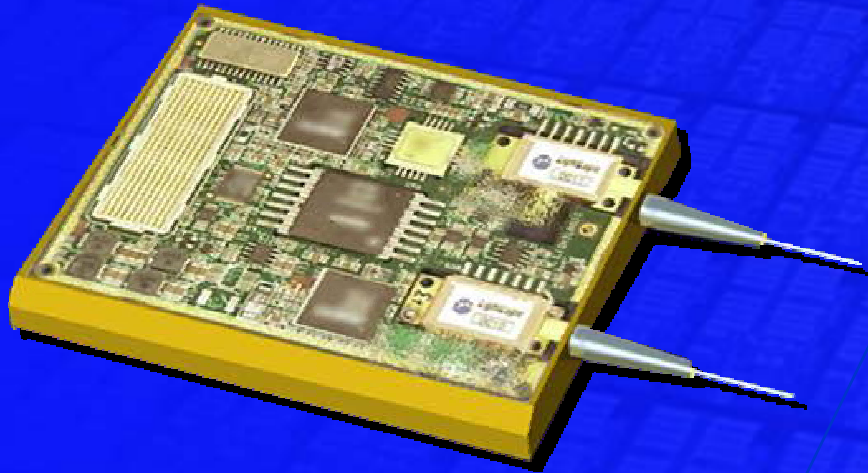
- As bandwidth increase electronic links utilize sophisticated encoding and equalization techniques that can lead to an increase in latency, power and area
- Optical links become attractive if the total cost and form factor of the link is comparable to or less than the total cost of the electrical link

Key Metrics: Bandwidth (with acceptable BER), cost/manufacturability area, power, latency

Opportunities for III-V electronics

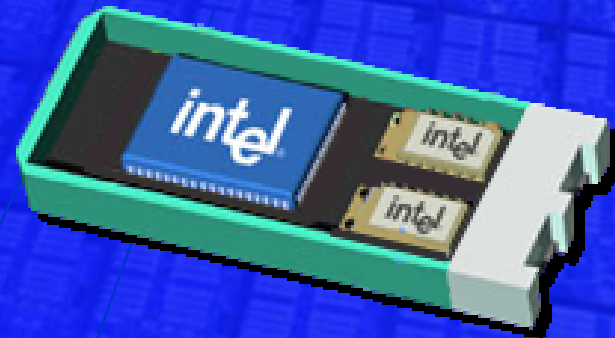
- **Silicon (CMOS, SiGe HBT) will continue to provide the high speed electronics:**
 - SiGe is very competitive with InP for speed
- **III-V electronics can play a big role if ultra compact monolithic transceivers can be developed specifically for chip to chip I/O at low cost:**
 - Every serial I/O link needs two transceivers
 - VCSEL, modulator (if needed), driver, detector and TIA are all integrated onto a monolithic InP substrate

Optical Module Integration for Telecom



Today
10+ Chips

4 Process Technologies



Future (90nm)
3 Chips

2 Process Technologies

4x Cost Reduction
3x Power Reduction

Critical needs

- **Area of focus**
 - **Low cost scalable sources:**
 - Direct modulated are desirable
 - External modulators (Polymer/LiNo₃, HV vs LV) are OK provided the integration and added drive electronics does not lead to a cost or form factor penalty.
 - **High performance detectors**
 - **Low cost packaging technologies for coupling sources, electronics and detectors**
 - **High volume manufacturing technologies:**
 - Couple sources and detectors either with waveguides or free space links
 - Compatibility with established manufacturing practices

Optical interconnect roadmap as seen today (2002)

	2 – 5 Years	5 – 10 Years	10+ Years
Chip to Chip < 20 Inches			
Board to Board < 30 Inches			
Box to Box < 3 m			

Optical

- **Copper interconnects are expected to scale in the next 3 – 5 year to 10 Gb/Sec at < 20 inches**

Conclusions

- Copper signaling has the potential to be developed to the 10 – 20 Gb/Sec regime for < 20 inch distances:
 - No physical barriers
 - Advanced circuit techniques
 - New PCB materials
- Optical signaling has great advantages and future potential due to unlimited bandwidth and no crosstalk and EMI:
- For mainstream deployment several factors need to be addressed:
 - Cost must be reduced to be comparable to electrical signaling
 - Address the specific needs of chip to chip interconnects
 - New packaging and integration strategies must be developed
 - Manufacturing techniques must be developed for high volume integration

Acknowledgments

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